

ABSTRACT OF THE DISCLOSURE

An accelerated test method evaluates, under accelerated conditions (a temperature T_2 and a voltage V_2), an endurance characteristic of a ferroelectric memory device having a capacitor element including a ferroelectric film under actual operating conditions (a temperature T_1 and a voltage V_1). An acceleration factor (K) required to evaluate the endurance characteristic is derived by using an expression: $\log K = A(1/V_1 - 1/V_2) + B(1/V_1 T_1 - 1/V_2 T_2)$ (where each of A and B is a constant).